Abstracts

A New Method to Calculate Parameters of Configurable Integrated Test Model

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A configurable integrated test (CIT) model has been developed for GaAs MMIC manufacturing control. The optimal process/test strategy of a MMIC in production phase can be predicted from this model. A new method using optimization concept is demonstrated to calculate parameters of the CIT model from process/test history. This method will estimate realistic screening probabilities and hence predict optimal test strategy accurately. The description of this new method and examples are presented in this paper.

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